

Optical absorption measurements in sapphire

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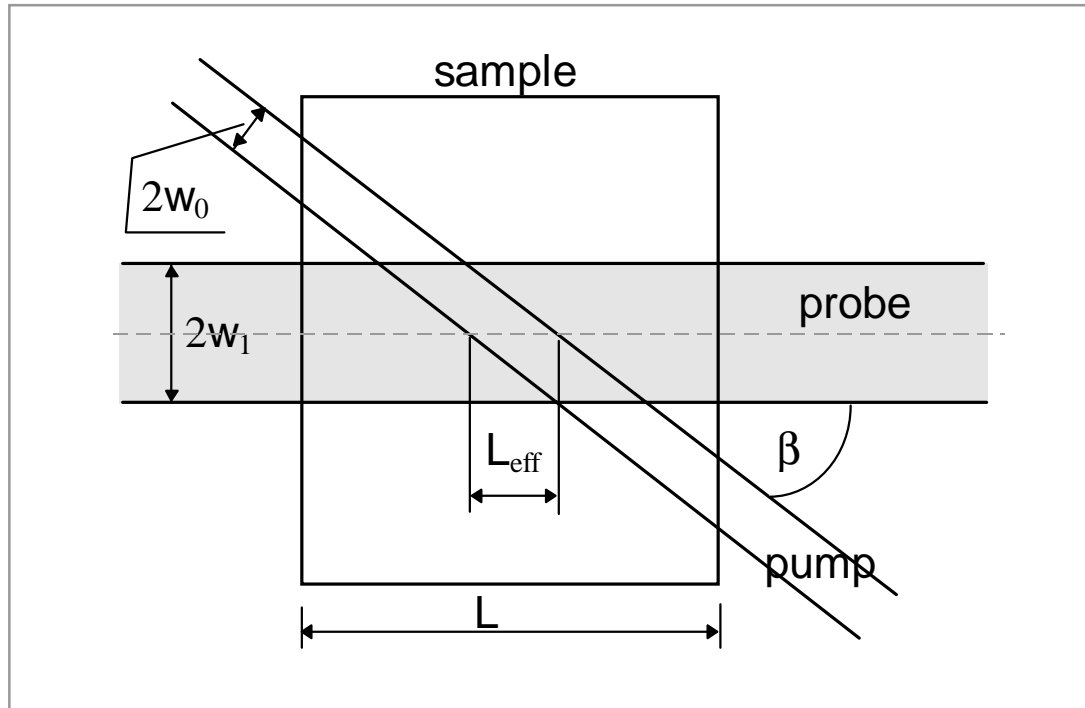
Optical absorption measurements in sapphire

OUTLINE

- **Background**
- **Photothermal technique**
- **As-grown sapphire**
- **Annealed sapphire**
- **How to go below 40 ppm/cm**
- **Prospects**



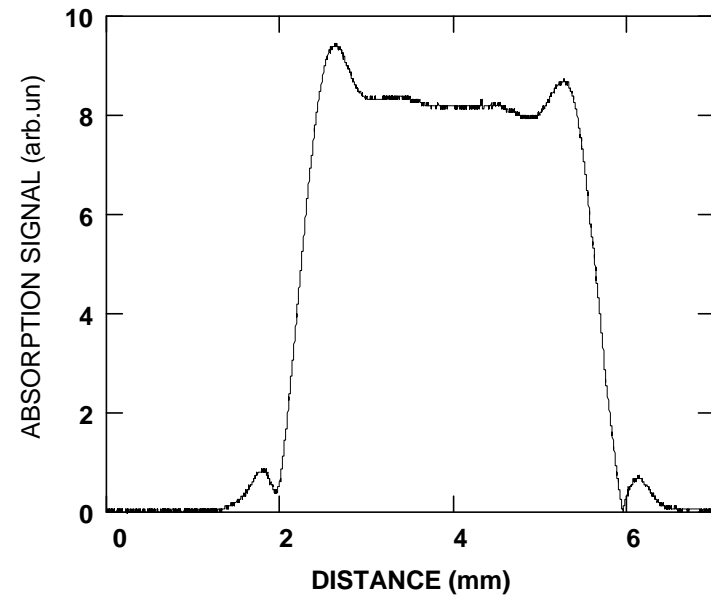
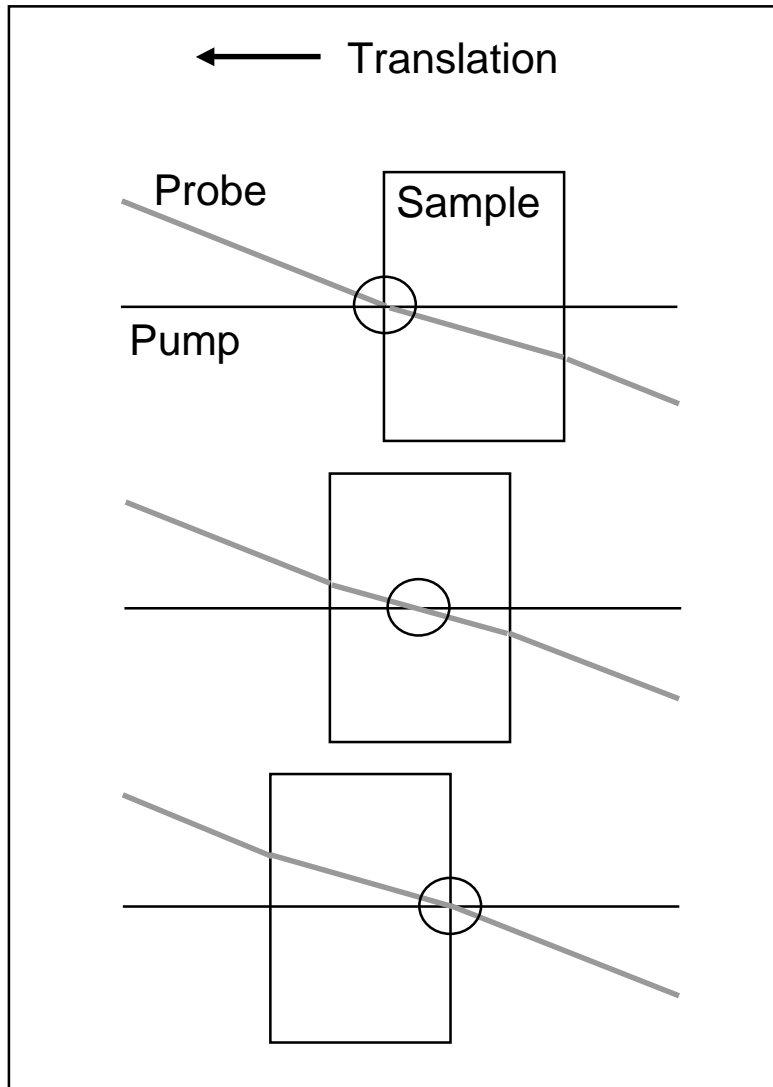
Space resolution



$$L_{eff} = \sqrt{\frac{\pi}{2}} \frac{w_0}{\sin \beta}$$

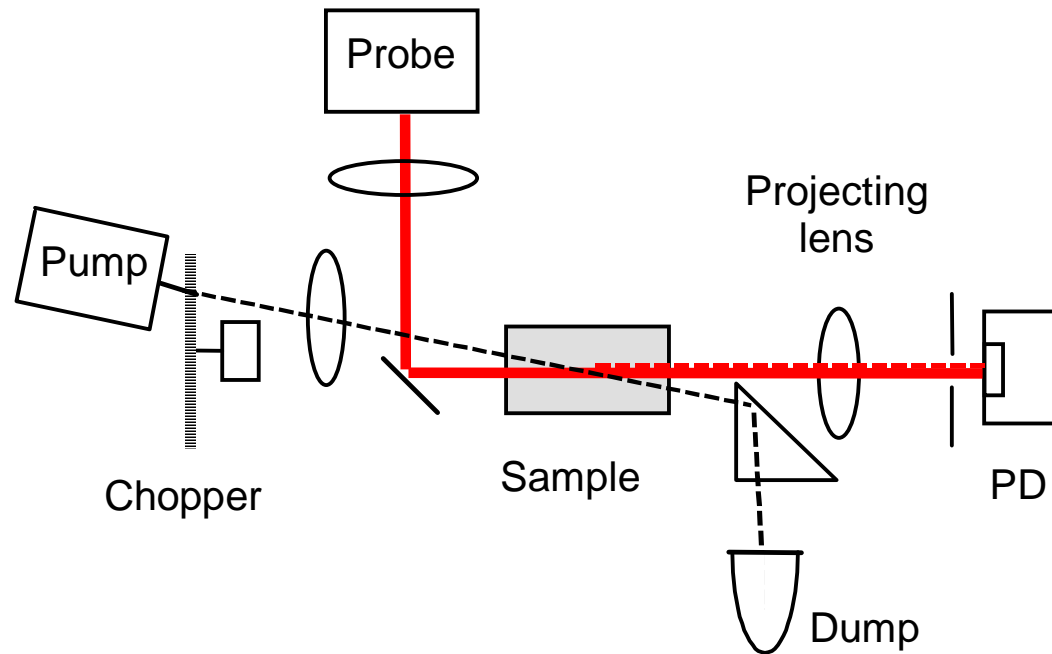
$$\alpha = \kappa \frac{P}{L_{eff}}$$

Space resolution: surface-to-surface scan



Example: 3 mm-thick neutral filter, 15%-absorbing
 $L_{eff} = 0.25$ mm

Photothermal Common-path Interferometer (PCI)



| | | | |
|-------------|-----------|--------------------|-----------------------|
| Pump waist | 50 μ | Chopping frequency | 380 Hz (10Hz - 2 kHz) |
| Probe waist | 120 μ | Crossing angle | 1° - 20° (in air) |
| Pump power | 5 W | Probe power | 0.5 mW |

- ac-component of probe distortion is detected by photodiode + lock-in
- absorption coefficient of 10^{-7} cm^{-1} can be detected with a 5 W pump
- **crossed beams** help to avoid false signals from optics and surfaces of the sample

Data on sapphire crystals (1998)

| Crystal | α (ppm/cm) | | Scattering | Fluorescence |
|---|--|--|-------------------------------|--|
| | 532nm | 1064nm | | |
| 'Window' 3mm-thick | 1400* | 81 | No | 2×10^{-3} F, Ti ³⁺ |
| CS 'White' #0 | 415* (bulk, anomaly near the surface) | 41 (bulk, anomaly near the surface) | Large near the surface | 1×10^{-3} F, Ti ³⁺ (bulk) |
| CS 'White' #1 | 1600 | 84 | No | 3×10^{-4} F |
| CS 'White' #2 | 1310 | 72 | Weak band in the bulk | 1×10^{-3} F |
| CS 'White' (Perth) | 1910 | 129 | Yes, broad band near one face | 3×10^{-3} F |
| CS 'Hemex Ultra' | 1150 | 188 | No | 1×10^{-4} F |
| 0.1% Ti-doped (reference #2) | 0.68/cm (total) 0.145/cm (thermal part) | 6400 | Yes, macro-defects | F, Ti ³⁺ |
| 0.05% Ti-doped laser rod (reference #1) | - | 19000** | - | 0.7F, Ti ³⁺ |

* 514 nm

** Absorption measured directly

Relative fluorescence brightness estimated with calibrated neutral filters,
Ti-doped reference #2 brightness denoted as F

Data on sapphire crystals (1999)

| Crystal | α (ppm/cm) | | Scattering | Fluorescence |
|--------------------------------------|--|--|------------------------|--|
| | 514nm | 1064nm | | |
| CS 'White', H ₂ -annealed | 605 | 53 | No | $\approx 2 \times 10^{-4}$ F |
| CS 'White', O ₂ -annealed | 600 (bulk, anomaly near the surface) | 47 (bulk, anomaly near the surface) | Large near the surface | $\approx 2 \times 10^{-4}$ F (bulk) |
| Substrate (TRW) | - | 66 | No | - |
| 'Window' 3mm-thick | 1400* | 81 | No | 2×10^{-3} F, Ti ³⁺ |
| 0.1% Ti-doped (reference #2) | 0.68/cm (total) 0.145/cm (thermal part) | 6400 | Yes, macro-defects | F, Ti ³⁺ |

Relative fluorescence brightness estimated with calibrated neutral filters, Ti-doped reference #2 brightness denoted as F

Data on sapphire crystals (2000)

Crystal Systems, Inc.

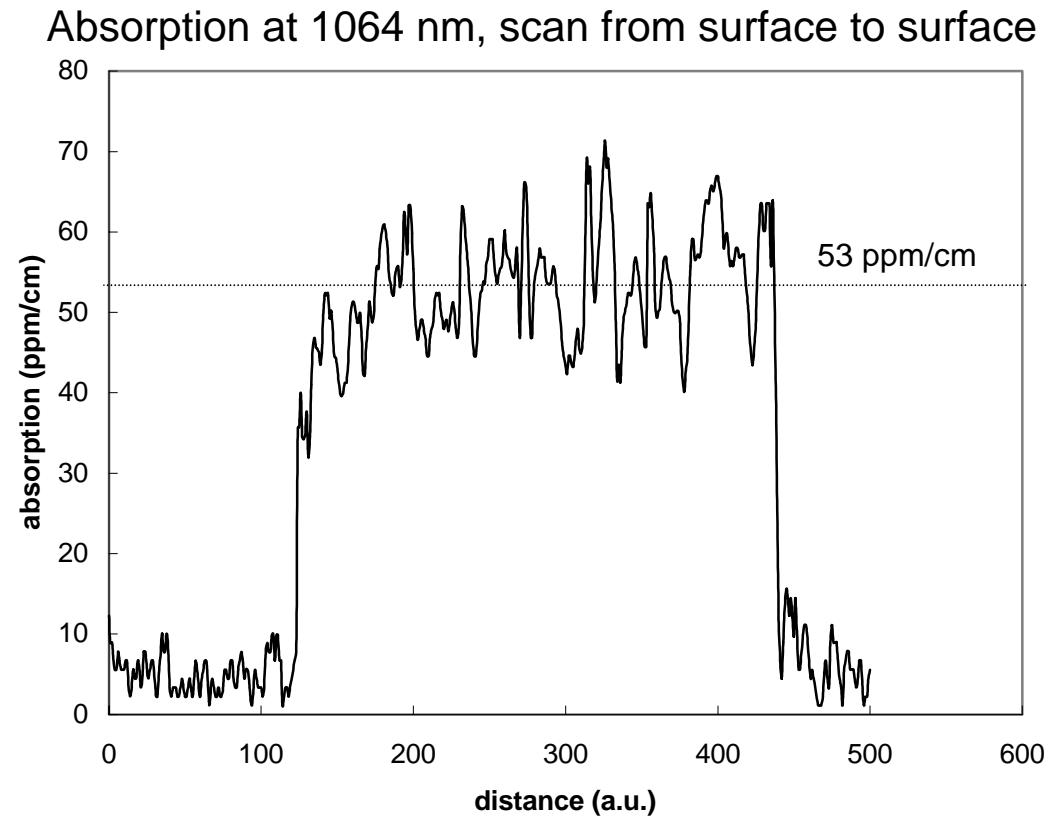
| Crystal | α (ppm/cm) | | Scattering | Fluorescence |
|---------|-------------------|--------|------------|------------------------|
| | 514nm | 1064nm | | |
| 1T | 1730 | 124 | No | 10×10^{-5} F |
| 1M | 1800 | 103 | No | 5×10^{-5} F |
| 1B | 1430 | 91 | No | 2.5×10^{-5} F |
| 2T | 900 | 57 | No | 4×10^{-4} F |
| 2M | 900 | 87 | No | 10×10^{-4} F |
| 2B | 1410 | 92 | No | 40×10^{-4} F |
| 3T | 920 | 62 | No | 10×10^{-5} F |
| 3M | 1470 | 121 | No | 5×10^{-5} F |
| 3B | 840 | 66 | No | 5×10^{-5} F |
| 4T | 830 | 46 | No | 10×10^{-4} F |
| 4M | 1200 | 126 | No | 2×10^{-4} F |
| 4B | 1200 | 94 | No | 1×10^{-4} F |

Nuclear Research Center – Negev, ISRAEL

| Crystal | α (ppm/cm) | | Scattering | Fluorescence |
|---------|-------------------|--------|------------|----------------------|
| | 514nm | 1064nm | | |
| 1579 | 1570 | 147 | No | 2×10^{-3} F |
| 1958 | 1600 | 140 | No | 2×10^{-3} F |
| 1741 | 1560 | 211 | No | 2×10^{-3} F |

Annealed sapphire data

20 mm-long, H₂-annealed sample

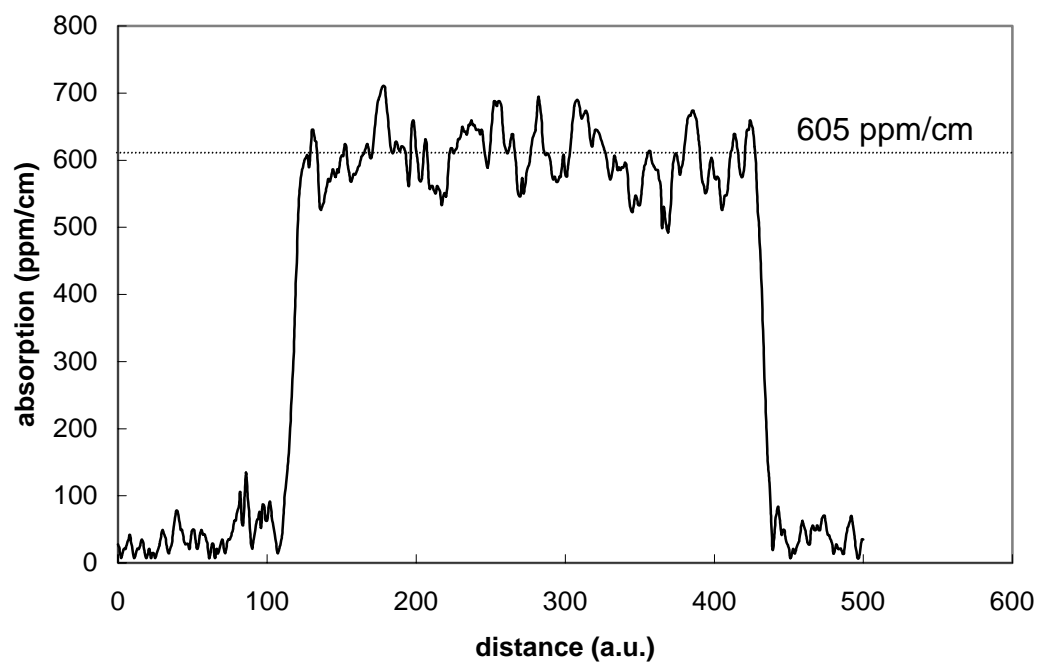


- Reference sample: Ti-doped sapphire with the absorption of 6400 ppm/cm at 1064 nm

Annealed sapphire data

20 mm-long, H₂-annealed sample

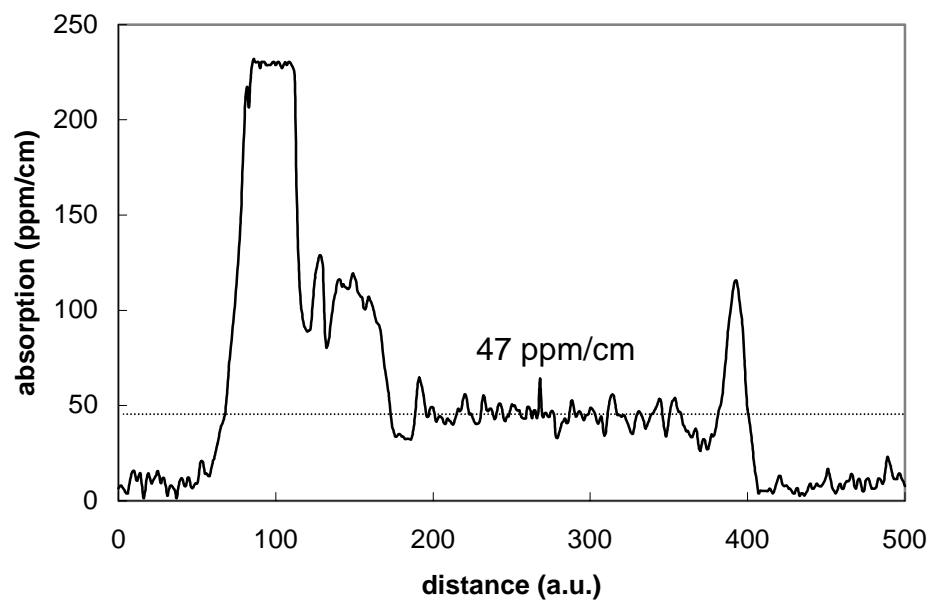
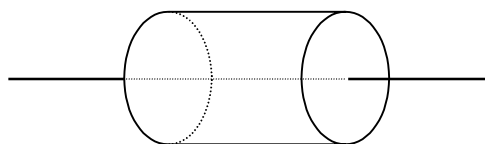
Absorption at 514 nm, scan from surface to surface



Annealed sapphire data

20 mm-long, O₂-annealed sample

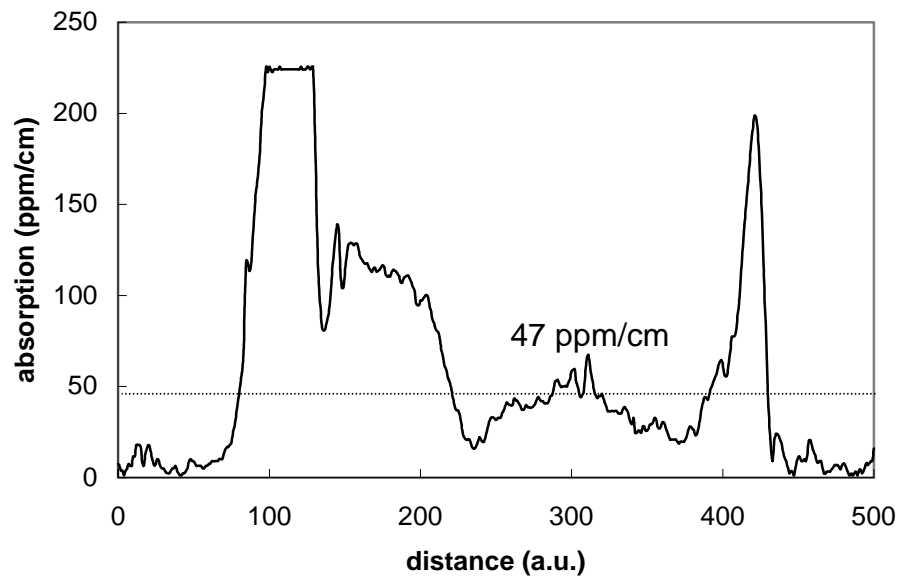
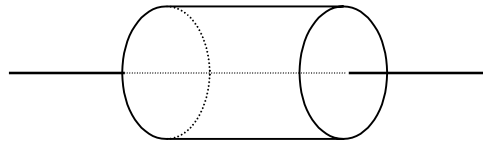
Absorption at 1064 nm, scan from surface to surface



Annealed sapphire data

20 mm-long, O₂-annealed sample

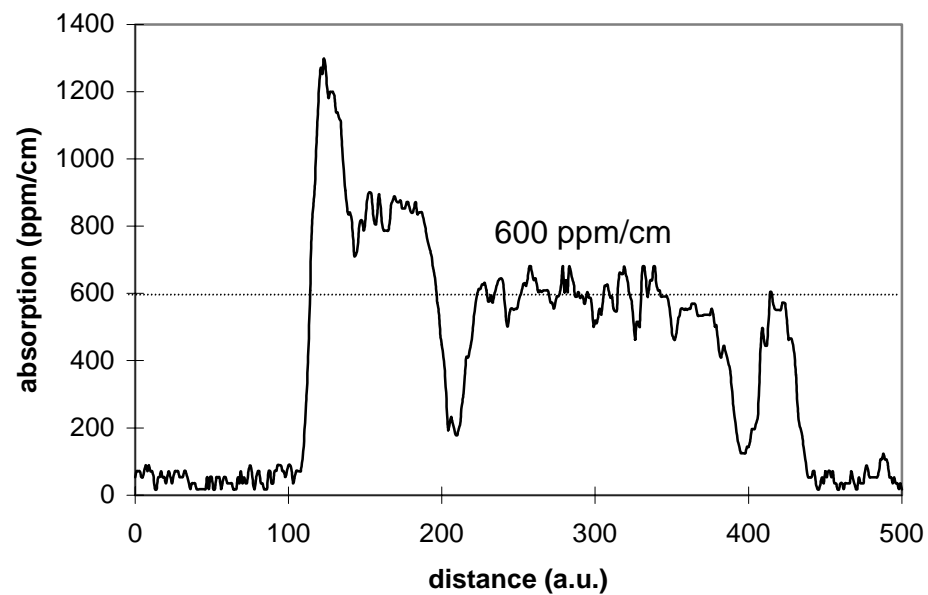
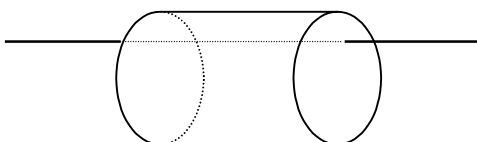
Absorption at 1064 nm, scan from surface to surface



Annealed sapphire data

20 mm-long, O₂-annealed sample

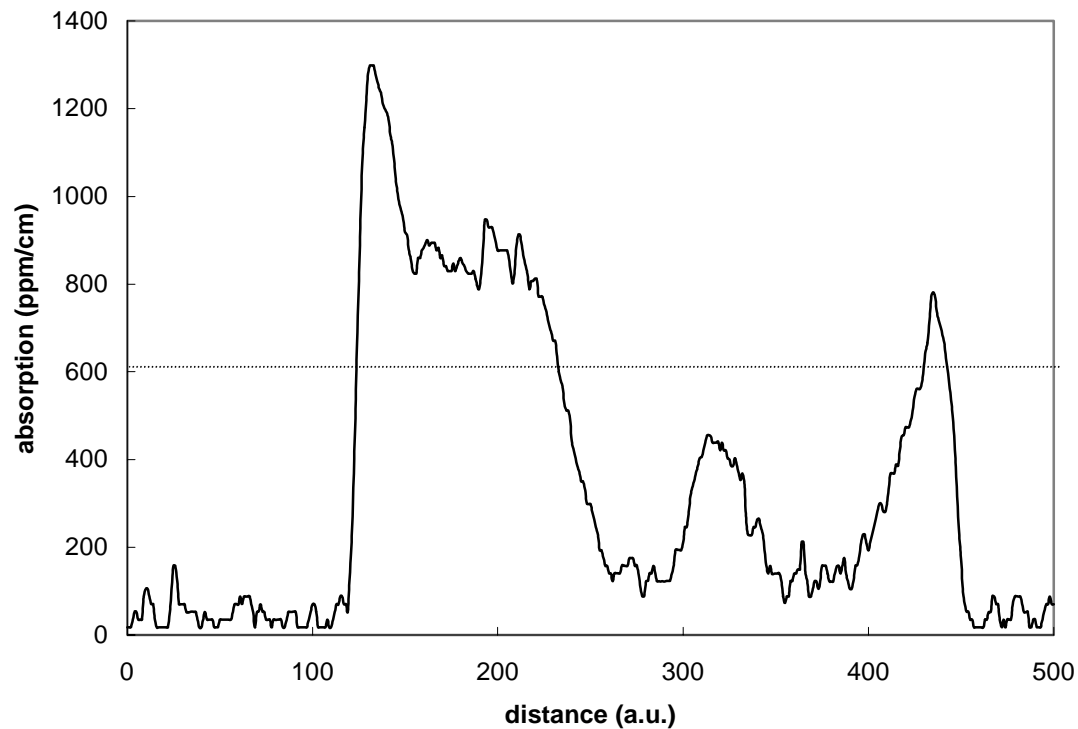
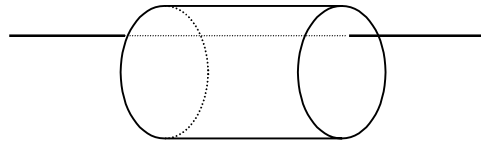
Absorption at 514 nm, scan from surface to surface



Annealed sapphire data

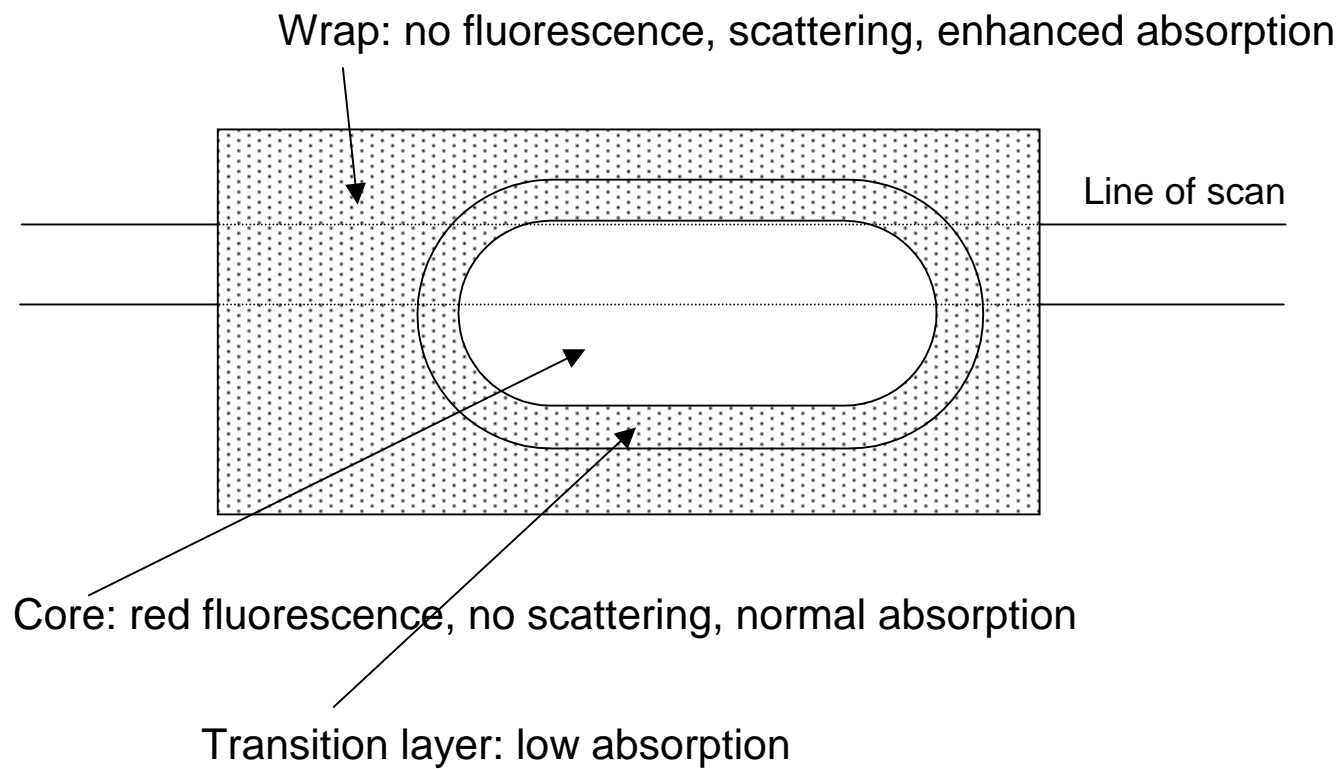
20 mm-long, O₂-annealed sample

Absorption at 514 nm, scan from surface to surface



Model

O₂-annealed sample



Conclusions

- ❖ The best as-grown sapphire shows 40 ppm/cm of absorption at 1064 nm
- ❖ H₂-annealed sapphire shows no change in absorption, fluorescence or scattering
- ❖ O₂-annealed sapphire shows a complex response to oxidation with local decrease of both IR and green absorption
- ❖ Defects responsible for current IR and green absorption levels are yet to be identified
- ❖ Proper annealing may offer means to reach the 10-15 ppm/cm level. Further decreases will depend on the ability to identify and eliminate specific defects

